

S16926DQ

Dual N-Channel 2.5V Specified PowerTrench® MOSFET

General Description

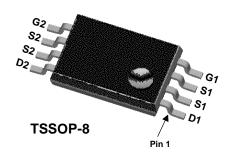
This N-Channel 2.5V specified MOSFET is a rugged gate version of Fairchild's Semiconductor's advanced PowerTrench process. It has been optimized for power management applications with a wide range of gate drive voltage (2.5V-12V).

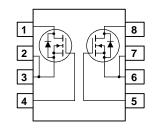
Applications

- · Load switch
- Motor drive
- DC/DC conversion
- · Power management

Features

- 5.5 A, 20 V. $R_{DS(ON)} = 0.021 \; \Omega \; @ \; V_{GS} = 4.5 \; V$ $R_{DS(ON)} = 0.035 \; \Omega \; @ \; V_{GS} = 2.5 \; V$
- Extended V_{GSS} range (±12V) for battery applications
- · Low gate charge
- High performance trench technology for extremely low $R_{\mbox{\scriptsize DS(ON)}}$
- Low profile TSSOP-8 package





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		20	V
V _{GSS}	Gate-Source Voltage		±12	V
I _D	Drain Current - Continuous	(Note 1a)	5.5	А
	- Pulsed		30	
P _D	Power Dissipation	(Note 1a)	1.0	W
		(Note 1b)	0.6	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	125	°C/W
		(Note 1b)	208	

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
6926	SI6926DQ	13"	12mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics		I		I	I
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA,Referenced to 25°C		14		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 16 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 12 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -12 \text{ V}$ $V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.6	0.8	1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to $25^{\circ}C$		-3.2		mV/°C
R _{DS(on)}	Static Drain-Source	$V_{GS} = 4.5 \text{ V}, \qquad I_D = 5.5 \text{ A}$		17	21	mΩ
	On–Resistance	$V_{GS} = 2.5 \text{ V}, \qquad I_{D} = 4.2 \text{ A}$		24	35	
		$V_{GS} = 4.5 \text{ V}, I_D = 5.5 \text{A}, T_J = 125 ^{\circ}\text{C}$		23	34	
I _{D(on)}	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	30			Α
g _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_{D} = 5.5 \text{ A}$		26		S
Dynamic	: Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 10 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		1082		pF
Coss	Output Capacitance	f = 1.0 MHz		277		pF
C _{rss}	Reverse Transfer Capacitance	7		130		pF
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$\begin{array}{cccccccccccccccccccccccccccccccccccc$		8	20	ns
t _r	Turn-On Rise Time			8	27	ns
t _{d(off)}	Turn-Off Delay Time			24	38	ns
t _f	Turn-Off Fall Time	7		8	16	ns
Q_g	Total Gate Charge	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 5.5 \text{ A},$		12	17	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 4.5 V		2		nC
Q_{gd}	Gate-Drain Charge			3		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain–Source				0.83	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 0.83 \text{ A} \text{(Note 2)}$		0.7	1.2	V

^{1.} $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.

a) R $_{\rm \theta JA}$ is 125°C/W (steady state) when mounted on a 1 inch² copper pad on FR-4. b) R $_{\rm \theta JA}$ is 208 °C/W (steady state) when mounted on a minimum copper pad on FR-4.

^{2.} Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

Typical Characteristics

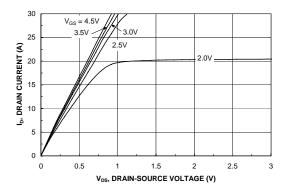


Figure 1. On-Region Characteristics.

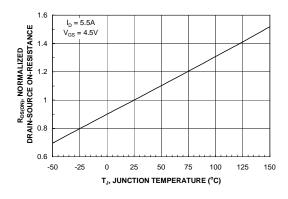


Figure 3. On-Resistance Variation with Temperature.

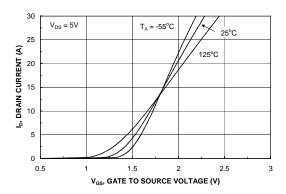


Figure 5. Transfer Characteristics.

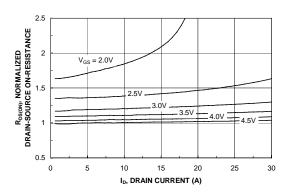


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

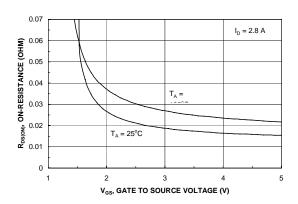


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

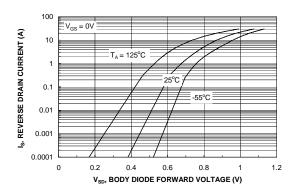
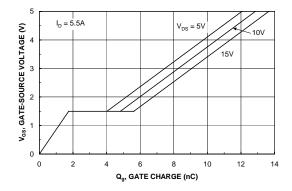


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



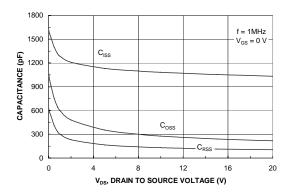
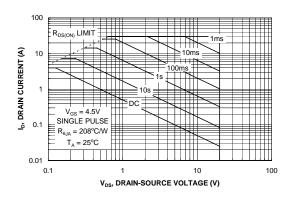


Figure 7. Gate Charge Characteristics.





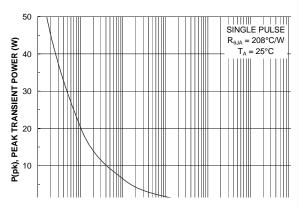


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

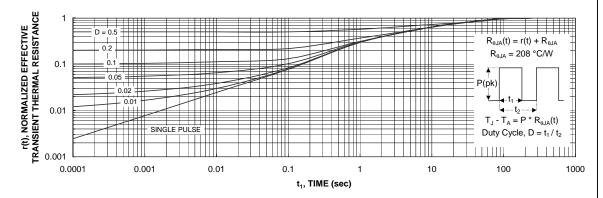


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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